

APR 26 2006
5005.1107

UNITED STATES PATENT & TRADEMARK OFFICE

Re: Application of: **Frank SIECKMANN et al.**
Serial No.: To Be Assigned
Filed: Herewith as national phase of International
Application No. PCT/EP2004/052600, filed 21 October
2004
For: **METHOD FOR AUTOMATIC PRODUCTION OF
LASER CUTTING LINES IN LASER MICRO-
DISSECTION**
Customer No.: 23280

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

April 19, 2006

Sir:

In accordance with the provisions of 37 C.F.R. § 1.97, Applicant hereby makes of record the documents listed on the accompanying PTO-1449 Form (1 page) for consideration by the Examiner in connection with the examination of the above-identified patent application. While the references are being submitted herewith, some or all of the references may not constitute prior art under the U.S. patent laws.

This Information Disclosure Statement is filed under 37 C.F.R. §1.97 (b), before the mailing date of a First Office Action, therefore no fee is believed due. In the event any

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additional fee is due in connection with this response or if any fee has been overpaid, the deficiency or overpayment should be charged to our Deposit Account No. 50-0552.

It is respectfully requested that the references cited in the accompanying PTO-1449 form be considered and made of record. It is respectfully submitted that the pending claims are patentable over all of the references made of record at this time.

Respectfully submitted,
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FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. <i>101370253</i>	APPLICATION NO. <i>101370253</i> To be assigned
LIST OF PRIOR ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Frank SIECKMANN et al.	
				FILING DATE Herewith	GROUP To be assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
	A01	4,741,043	Apr. 26, 1988	Bacus	382	6	
	A02	5,843,657	Dec. 1, 1998	Liotta et al.	435	6	
	A03	5,998,129	Dec. 7, 1999	Schütze et al.	435	4	
	A04	2002/0090122	Jul. 11, 2002	Baer et al.	382	128	
	A05	2002/0164678	Nov. 7, 2002	Ganser et al.	435	40.5	
	A06	6,787,301	Sep. 7, 2004	Ganser et al.	435	4	
	A07	6,907,798	Jun. 21, 2005	Ganser et al.	73	864.41	
	A08	5,031,099	Jul. 9, 1991	Kettler	364	413.08	
	A09	5,843,644	Dec. 1, 1998	Liotta et al.	435	6	
	A10	6,713,264	Mar. 30, 2004	Luttermann et al.	435	7.1	
	A11	6,991,714	Jan. 31, 2006	Gauss et al.	204	462	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	YES	NO
		WO 01/73398	Oct. 4, 2001	WO-WIPO			See Abstract		
	A13	DE 100 18 251	Oct. 25, 2001	DE-Germany			Corresponds to US 6,907,798		
	A14	DE 100 43 506	Dec. 6, 2001	DE-Germany			Corresponds to US 6,787,301		
	A15	DE 196 36 074	Mar. 26, 1998	DE-Germany			See Intl. Search Report for PCT/EP2004/052600; see English Abstract		
	A16	DE 695 10 925	Feb. 17, 2000	DE-Germany			Corresponds to US 5,843,644		
	A17	DE 42 11 904	Nov. 19, 1992	DE-Germany			See Abstract		
	A18	DE 196 29 141	Apr. 16, 1998	DE-Germany			Corresponds to US 6,713,264		
	A19	DE 38 36 716	May 3, 1990	DE-Germany			Corresponds to US 5,031,099		
	A20	DE 198 15 400	Oct. 14, 1999	DE-Germany			Corresponds to US 6,991,714		

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

A21	International Search Report for PCT/EP2004/052600 (4 pages)
A22	P.A.L.M. Microlaser Technologies: "PALM MicroBeam IP-MS + Metafer P, February 2003 (4 pages)
A23	ARCTURUS: "Laser Capture Microdissection (LCM) Systems", XP-002315059 (6 pages)
A24	B. J. SCHACHTER et al.: "Some Experiments in Image Segmentation by Clustering of Local Feature Values", XP-002269476, Pattern Recognition, Vol. 11, Pattern Recognition Society, Pergamon Press Ltd., Great Britain, pp.19-28

EXAMINER	DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.